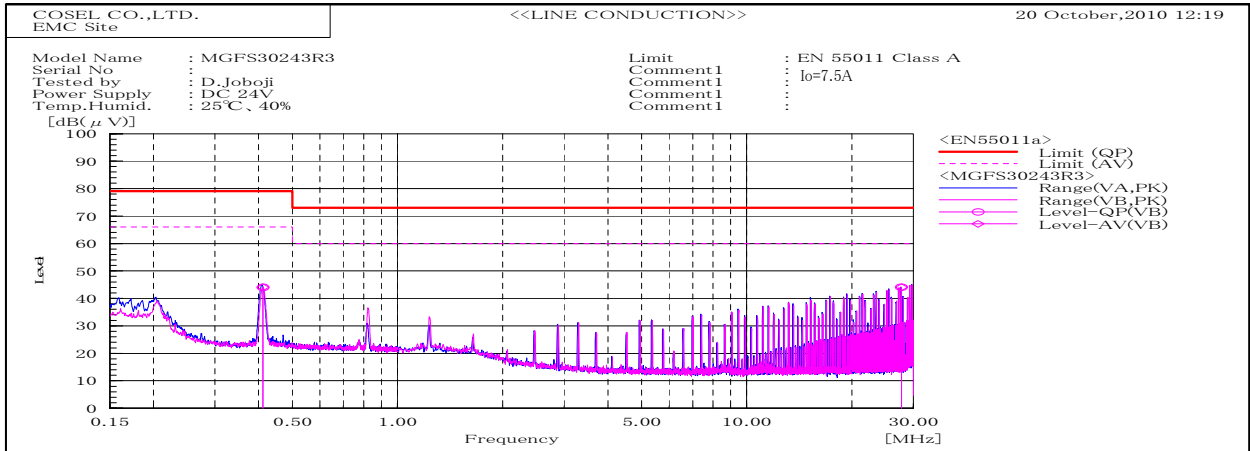
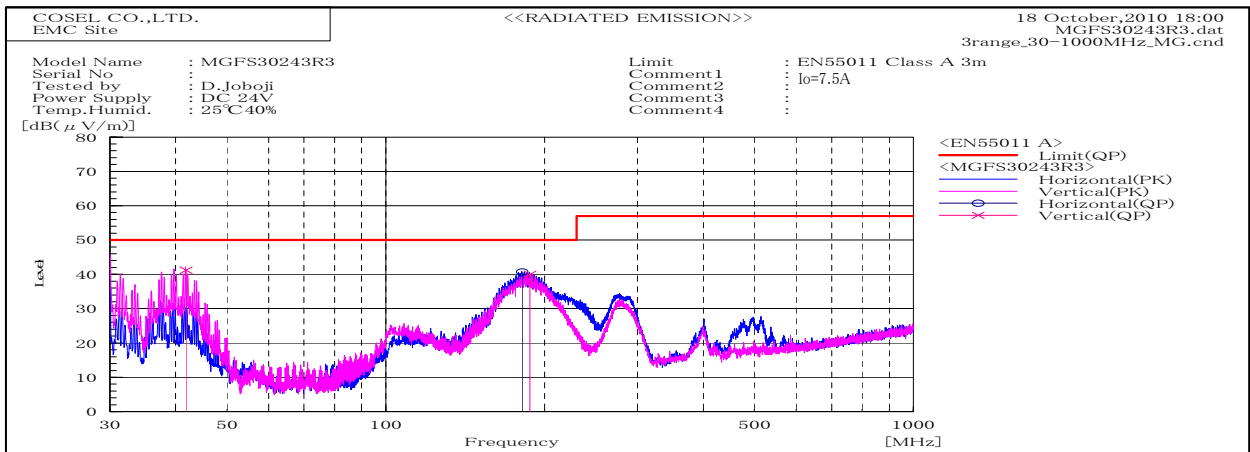


DATA SHEET		Date	20-Oct-10
Model	MGFS30243R3	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	D.Joboji



Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.41203		VB	34	34.1	10	44	44.1	79	66	35	21.9	Pass	
27.7314		VB	33.1	33.1	11	44.1	44.1	73	60	28.9	15.9	Pass	



Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)	Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	QP	QP				
41.826V		Stable	60.7	-19.5		41.2		50	8.8	Pass	102	83
181.474H		Stable	62.9	-22.2		40.7		50	9.3	Pass	155	181
187.759V		Stable	62.1	-22.1		40		50	10	Pass	108	65

# DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

## 1. Line conduction



## 2. Radiated emission



## Conditions

Test : EMI  
 Model Name : MGFS3024□□/MGFW3024□□

○Photographs of Test Set-Up

### LINE CONDUCTION



### RADIATED EMISSION



○Testing circuitry

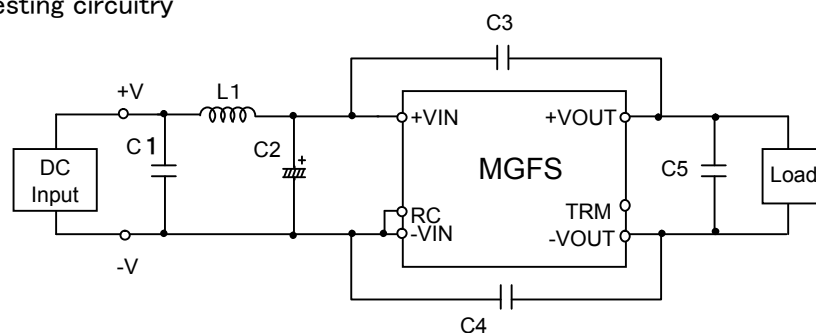


Fig.1 Testing circuitry 1

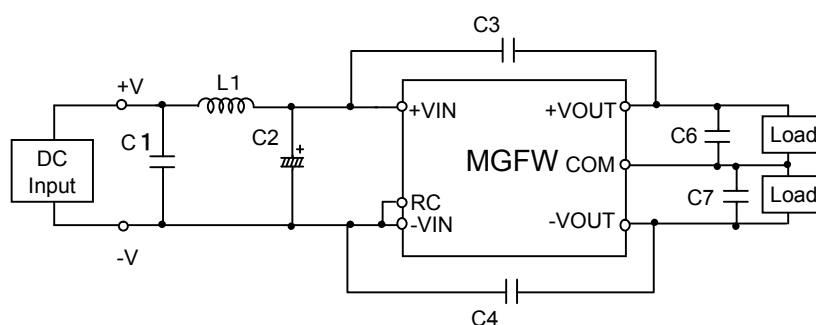


Fig.2 Testing circuitry 2

L1	: 0.6uH	CI8C-0R6	(KORIN ELECTRONICS)
C1	: 50V 4.7 $\mu$ F	Ceramic Capacitor	
C2	: 50V 100 $\mu$ F	Electrolytic Capacitor	
C3,C4	: 2kV 1000pF	Ceramic Capacitor	
C5,C6,C7	: 25V 22 $\mu$ F	Ceramic Capacitor	